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Understanding [Embedded - CPLDs \(Complex Programmable Logic Devices\)](#)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details

Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	7.5 ns
Voltage Supply - Internal	2.375V ~ 2.625V
Number of Logic Elements/Blocks	4
Number of Macrocells	64
Number of Gates	1250
Number of I/O	36
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	44-TQFP
Supplier Device Package	44-TQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm7064btc44-7

MAX 7000B devices provide programmable speed/power optimization. Speed-critical portions of a design can run at high speed/full power, while the remaining portions run at reduced speed/low power. This speed/power optimization feature enables the designer to configure one or more macrocells to operate up to 50% lower power while adding only a nominal timing delay. MAX 7000B devices also provide an option that reduces the slew rate of the output buffers, minimizing noise transients when non-speed-critical signals are switching. The output drivers of all MAX 7000B devices can be set for 3.3 V, 2.5 V, or 1.8 V and all input pins are 3.3-V, 2.5-V, and 1.8-V tolerant, allowing MAX 7000B devices to be used in mixed-voltage systems.

MAX 7000B devices are supported by Altera development systems, which are integrated packages that offer schematic, text—including VHDL, Verilog HDL, and the Altera Hardware Description Language (AHDL)—and waveform design entry, compilation and logic synthesis, simulation and timing analysis, and device programming. Altera software provides EDIF 2.0.0 and 3.0.0, LPM, VHDL, Verilog HDL, and other interfaces for additional design entry and simulation support from other industry-standard PC- and UNIX-workstation-based EDA tools. Altera software runs on Windows-based PCs, as well as Sun SPARCstation, and HP 9000 Series 700/800 workstations.



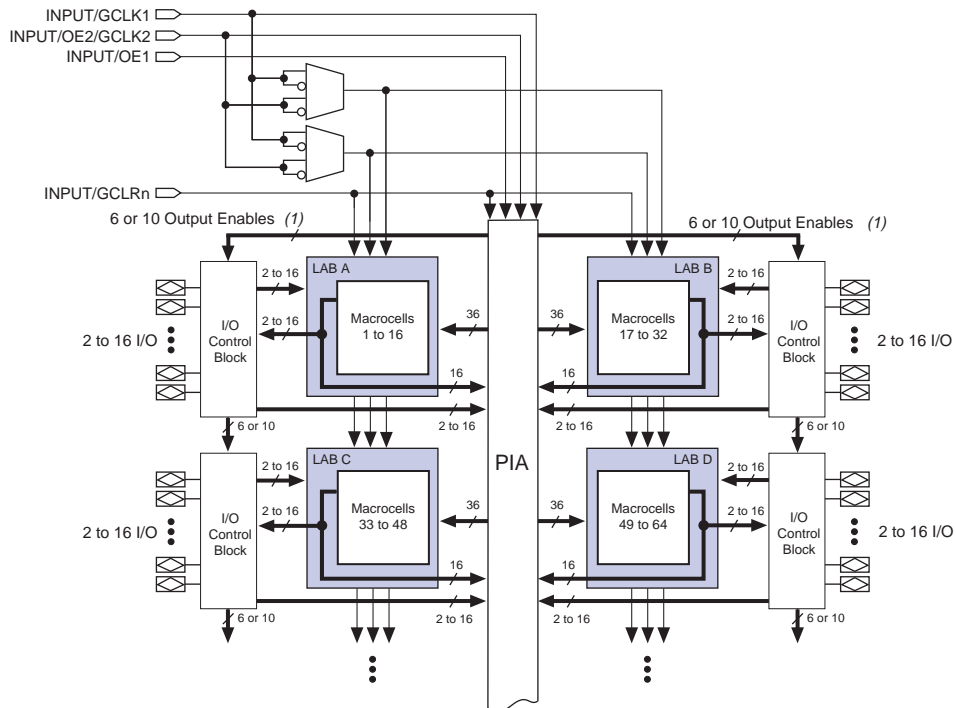
For more information on development tools, see the *MAX+PLUS II Programmable Logic Development System & Software Data Sheet* and the *Quartus Programmable Logic Development System & Software Data Sheet*.

Functional Description

The MAX 7000B architecture includes the following elements:

- LABs
- Macrocells
- Expander product terms (shareable and parallel)
- PIA
- I/O control blocks

The MAX 7000B architecture includes four dedicated inputs that can be used as general-purpose inputs or as high-speed, global control signals (clock, clear, and two output enable signals) for each macrocell and I/O pin. [Figure 1](#) shows the architecture of MAX 7000B devices.

Figure 1. MAX 7000B Device Block Diagram**Note:**

- (1) EPM7032B, EPM7064B, EPM7128B, and EPM7256B devices have six output enables. EPM7512B devices have ten output enables.

Logic Array Blocks

The MAX 7000B device architecture is based on the linking of high-performance LABs. LABs consist of 16 macrocell arrays, as shown in Figure 1. Multiple LABs are linked together via the PIA, a global bus that is fed by all dedicated input pins, I/O pins, and macrocells.

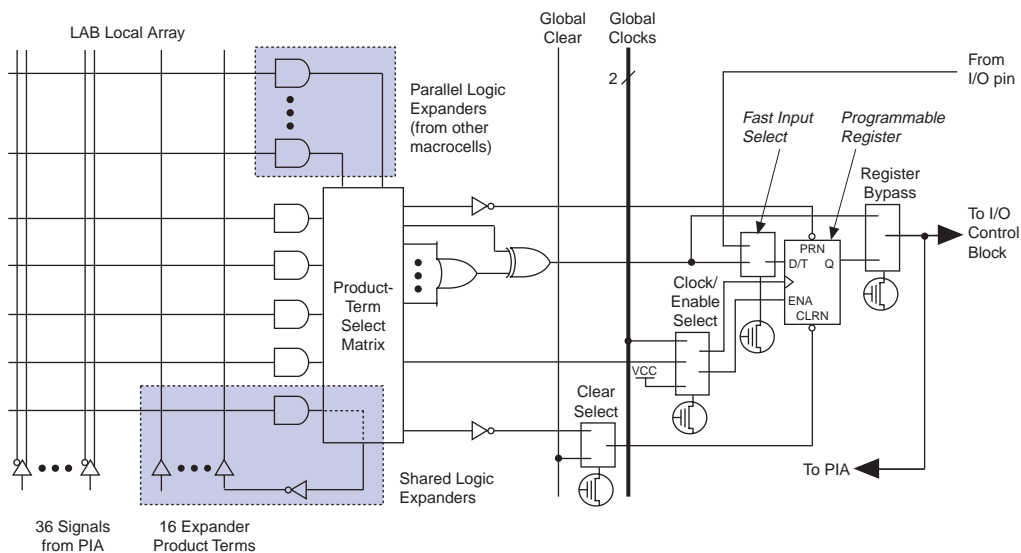
Each LAB is fed by the following signals:

- 36 signals from the PIA that are used for general logic inputs
- Global controls that are used for secondary register functions
- Direct input paths from I/O pins to the registers that are used for fast setup times

Macrocells

The MAX 7000B macrocell can be individually configured for either sequential or combinatorial logic operation. The macrocell consists of three functional blocks: the logic array, the product-term select matrix, and the programmable register. Figure 2 shows the MAX 7000B macrocell.

Figure 2. MAX 7000B Macrocell

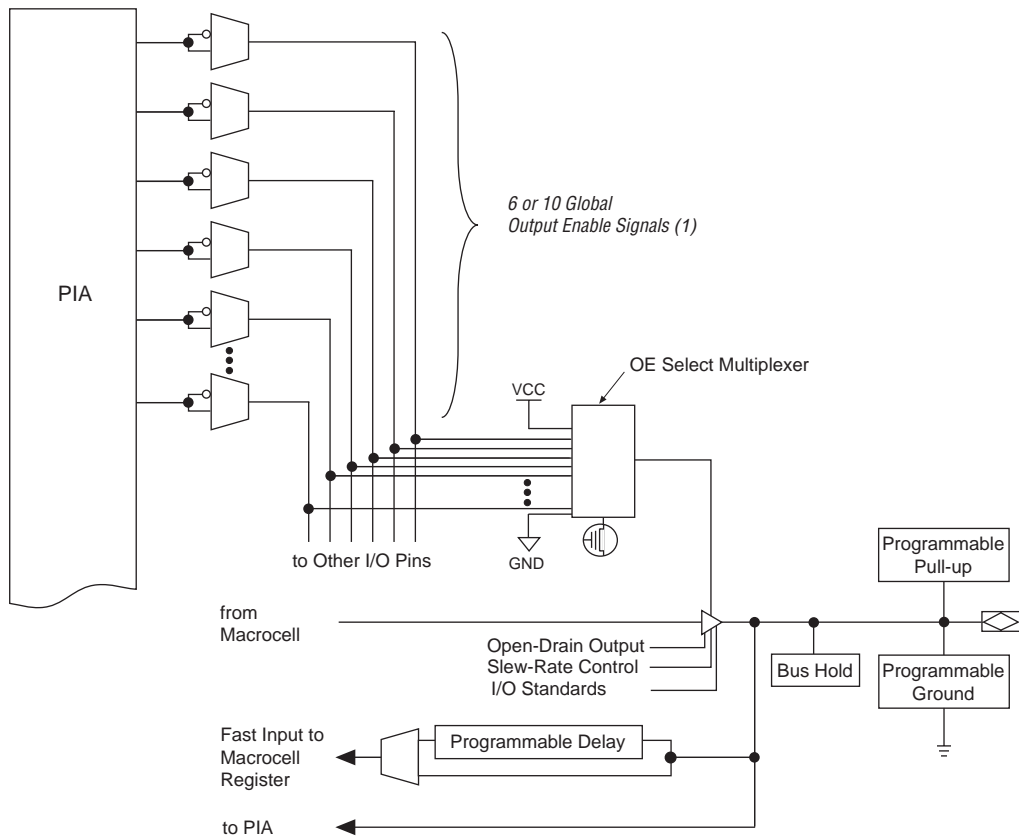


Combinatorial logic is implemented in the logic array, which provides five product terms per macrocell. The product-term select matrix allocates these product terms for use as either primary logic inputs (to the OR and XOR gates) to implement combinatorial functions, or as secondary inputs to the macrocell's register preset, clock, and clock enable control functions.

Two kinds of expander product terms ("expanders") are available to supplement macrocell logic resources:

- Shareable expanders, which are inverted product terms that are fed back into the logic array
- Parallel expanders, which are product terms borrowed from adjacent macrocells

Figure 6. I/O Control Block of MAX 7000B Devices

**Note:**

- (1) EPM7032B, EPM7064B, EPM7128B, and EPM7256B devices have six output enable signals. EPM7512B devices have ten output enable signals.

When the tri-state buffer control is connected to ground, the output is tri-stated (high impedance) and the I/O pin can be used as a dedicated input. When the tri-state buffer control is connected to V_{CC} , the output is enabled.

The MAX 7000B architecture provides dual I/O feedback, in which macrocell and pin feedbacks are independent. When an I/O pin is configured as an input, the associated macrocell can be used for buried logic.

In-System Programmability (ISP)

MAX 7000B devices can be programmed in-system via an industry-standard 4-pin IEEE Std. 1149.1 (JTAG) interface. ISP offers quick, efficient iterations during design development and debugging cycles. The MAX 7000B architecture internally generates the high programming voltages required to program EEPROM cells, allowing in-system programming with only a single 2.5-V power supply. During in-system programming, the I/O pins are tri-stated and weakly pulled-up to eliminate board conflicts. The pull-up value is nominally 50 k Ω .

MAX 7000B devices have an enhanced ISP algorithm for faster programming. These devices also offer an ISP_Done bit that provides safe operation when in-system programming is interrupted. This ISP_Done bit, which is the last bit programmed, prevents all I/O pins from driving until the bit is programmed.

ISP simplifies the manufacturing flow by allowing devices to be mounted on a PCB with standard pick-and-place equipment before they are programmed. MAX 7000B devices can be programmed by downloading the information via in-circuit testers, embedded processors, the Altera MasterBlaster communications cable, and the ByteBlasterMV parallel port download cable. Programming the devices after they are placed on the board eliminates lead damage on high-pin-count packages (e.g., QFP packages) due to device handling. MAX 7000B devices can be reprogrammed after a system has already shipped to the field. For example, product upgrades can be performed in the field via software or modem.

In-system programming can be accomplished with either an adaptive or constant algorithm. An adaptive algorithm reads information from the unit and adapts subsequent programming steps to achieve the fastest possible programming time for that unit. A constant algorithm uses a pre-defined (non-adaptive) programming sequence that does not take advantage of adaptive algorithm programming time improvements. Some in-circuit testers cannot program using an adaptive algorithm. Therefore, a constant algorithm must be used. MAX 7000B devices can be programmed with either an adaptive or constant (non-adaptive) algorithm.

The Jam Standard Test and Programming Language (STAPL), JEDEC standard JESD-71, can be used to program MAX 7000B devices with in-circuit testers, PCs, or embedded processors.



For more information on using the Jam language, see [Application Note 88 \(Using the Jam Language for ISP & ICR via an Embedded Processor\)](#) and [Application Note 122 \(Using STAPL for ISP & ICR via an Embedded Processor\)](#).

The ISP circuitry in MAX 7000B devices is compliant with the IEEE Std. 1532 specification. The IEEE Std. 1532 is a standard developed to allow concurrent ISP between multiple PLD vendors.

The instruction register length of MAX 7000B devices is ten bits. The MAX 7000B USERCODE register length is 32 bits. [Tables 7 and 8](#) show the boundary-scan register length and device IDCODE information for MAX 7000B devices.

Table 7. MAX 7000B Boundary-Scan Register Length

Device	Boundary-Scan Register Length
EPM7032B	96
EPM7064B	192
EPM7128B	288
EPM7256B	480
EPM7512B	624

Table 8. 32-Bit MAX 7000B Device IDCODE *Note (1)*

Device	IDCODE (32 Bits)			
	Version (4 Bits)	Part Number (16 Bits)	Manufacturer's Identity (11 Bits)	1 (1 Bit) (2)
EPM7032B	0010	0111 0000 0011 0010	00001101110	1
EPM7064B	0010	0111 0000 0110 0100	00001101110	1
EPM7128B	0010	0111 0001 0010 1000	00001101110	1
EPM7256B	0010	0111 0010 0101 0110	00001101110	1
EPM7512B	0010	0111 0101 0001 0010	00001101110	1

Notes:

- (1) The most significant bit (MSB) is on the left.
- (2) The least significant bit (LSB) for all JTAG IDCODEs is 1.



See [Application Note 39 \(IEEE 1149.1 \(JTAG\) Boundary-Scan Testing in Altera Devices\)](#) for more information on JTAG boundary-scan testing.

[Figure 8](#) shows the timing information for the JTAG signals.

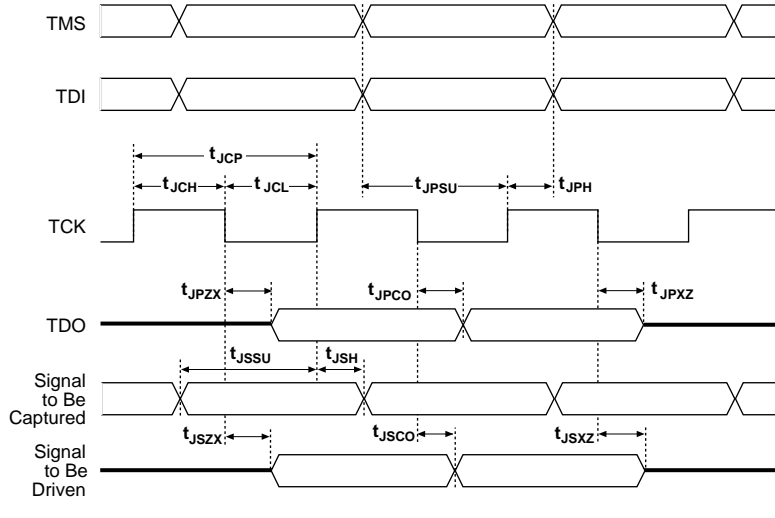
Figure 8. MAX 7000B JTAG Waveforms

Table 9 shows the JTAG timing parameters and values for MAX 7000B devices.

Table 9. JTAG Timing Parameters & Values for MAX 7000B Devices <i>Note (1)</i>				
Symbol	Parameter	Min	Max	Unit
t_{JCP}	TCK clock period	100		ns
t_{JCH}	TCK clock high time	50		ns
t_{JCL}	TCK clock low time	50		ns
t_{JPSU}	JTAG port setup time	20		ns
t_{JPH}	JTAG port hold time	45		ns
t_{JPCO}	JTAG port clock to output		25	ns
t_{JPZX}	JTAG port high impedance to valid output		25	ns
t_{JPXZ}	JTAG port valid output to high impedance		25	ns
t_{JSSU}	Capture register setup time	20		ns
t_{JSH}	Capture register hold time	45		ns
t_{JSCO}	Update register clock to output		25	ns
t_{JSZX}	Update register high impedance to valid output		25	ns
t_{JSXZ}	Update register valid output to high impedance		25	ns

Note:

(1) Timing parameters in this table apply to all V_{CCIO} levels.

Table 10. MAX 7000B MultiVolt I/O Support

V _{CCIO} (V)	Input Signal (V)				Output Signal (V)			
	1.8	2.5	3.3	5.0	1.8	2.5	3.3	5.0
1.8	✓	✓	✓		✓			
2.5	✓	✓	✓			✓		
3.3	✓	✓	✓				✓	✓

Open-Drain Output Option

MAX 7000B devices provide an optional open-drain (equivalent to open-collector) output for each I/O pin. This open-drain output enables the device to provide system-level control signals (e.g., interrupt and write enable signals) that can be asserted by any of several devices. It can also provide an additional wired-OR plane.

Programmable Ground Pins

Each unused I/O pin on MAX 7000B devices may be used as an additional ground pin. This programmable ground feature does not require the use of the associated macrocell; therefore, the buried macrocell is still available for user logic.

Slew-Rate Control

The output buffer for each MAX 7000B I/O pin has an adjustable output slew rate that can be configured for low-noise or high-speed performance. A faster slew rate provides high-speed transitions for high-performance systems. However, these fast transitions may introduce noise transients into the system. A slow slew rate reduces system noise, but adds a nominal delay of 4 to 5 ns. When the configuration cell is turned off, the slew rate is set for low-noise performance. Each I/O pin has an individual EEPROM bit that controls the slew rate, allowing designers to specify the slew rate on a pin-by-pin basis. The slew rate control affects both the rising and falling edges of the output signal.

Advanced I/O Standard Support

The MAX 7000B I/O pins support the following I/O standards: LVTTTL, LVCMOS, 1.8-V I/O, 2.5-V I/O, GTL+, SSTL-3 Class I and II, and SSTL-2 Class I and II.

Power Sequencing & Hot-Socketing

Because MAX 7000B devices can be used in a mixed-voltage environment, they have been designed specifically to tolerate any possible power-up sequence. The V_{CCIO} and V_{CCINT} power planes can be powered in any order.

Signals can be driven into MAX 7000B devices before and during power-up (and power-down) without damaging the device. Additionally, MAX 7000B devices do not drive out during power-up. Once operating conditions are reached, MAX 7000B devices operate as specified by the user.

MAX 7000B device I/O pins will not source or sink more than 300 μ A of DC current during power-up. All pins can be driven up to 4.1 V during hot-socketing.

Design Security

All MAX 7000B devices contain a programmable security bit that controls access to the data programmed into the device. When this bit is programmed, a design implemented in the device cannot be copied or retrieved. This feature provides a high level of design security, because programmed data within EEPROM cells is invisible. The security bit that controls this function, as well as all other programmed data, is reset only when the device is reprogrammed.

Generic Testing

MAX 7000B devices are fully functionally tested. Complete testing of each programmable EEPROM bit and all internal logic elements ensures 100% programming yield. AC test measurements are taken under conditions equivalent to those shown in [Figure 11](#). Test patterns can be used and then erased during early stages of the production flow.

Table 17. MAX 7000B Device Capacitance *Note (9)*

Symbol	Parameter	Conditions	Min	Max	Unit
C_{IN}	Input pin capacitance	$V_{IN} = 0\text{ V}$, $f = 1.0\text{ MHz}$		8	pF
$C_{I/O}$	I/O pin capacitance	$V_{OUT} = 0\text{ V}$, $f = 1.0\text{ MHz}$		8	pF

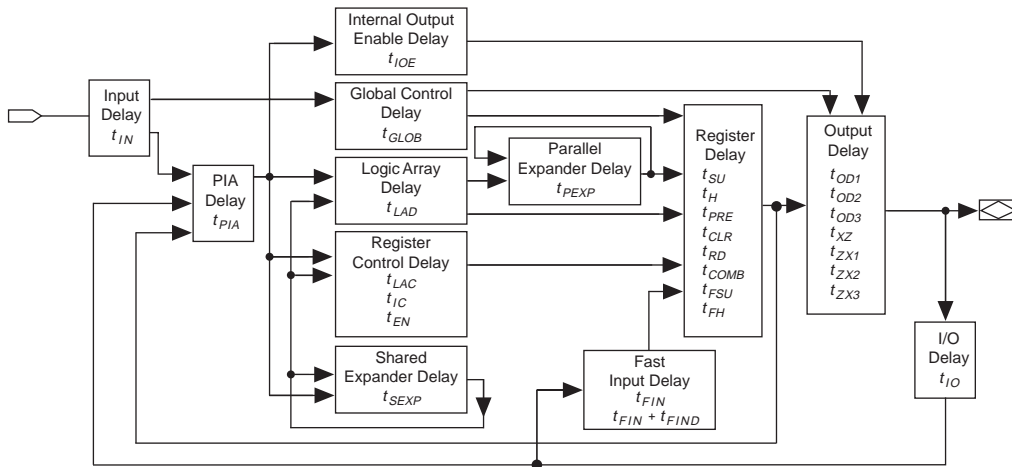
Notes to tables:

- (1) See the *Operating Requirements for Altera Devices Data Sheet*.
- (2) Minimum DC input voltage is -0.5 V . During transitions, the inputs may undershoot to -2.0 V or overshoot to 4.6 V for input currents less than 100 mA and periods shorter than 20 ns .
- (3) All pins, including dedicated inputs, I/O pins, and JTAG pins, may be driven before V_{CCINT} and V_{CCIO} are powered.
- (4) These values are specified under the Recommended Operating Conditions in [Table 15 on page 29](#).
- (5) The parameter is measured with 50% of the outputs each sourcing the specified current. The I_{OH} parameter refers to high-level TTL or CMOS output current.
- (6) The parameter is measured with 50% of the outputs each sinking the specified current. The I_{OL} parameter refers to low-level TTL or CMOS output current.
- (7) This value is specified for normal device operation. During power-up, the maximum leakage current is $\pm 300\text{ }\mu\text{A}$.
- (8) This pull-up exists while devices are being programmed in-system and in unprogrammed devices during power-up. The pull-up resistor is from the pins to V_{CCIO} .
- (9) Capacitance is measured at 25° C and is sample-tested only. Two of the dedicated input pins (OE1 and GCLRN) have a maximum capacitance of 15 pF .
- (10) The POR time for all 7000B devices does not exceed $100\text{ }\mu\text{s}$. The sufficient V_{CCINT} voltage level for POR is 2.375 V . The device is fully initialized within the POR time after V_{CCINT} reaches the sufficient POR voltage level.
- (11) These devices support in-system programming for -40° to 100° C . For in-system programming support between -40° and 0° C , contact Altera Applications.

Timing Model

MAX 7000B device timing can be analyzed with the Altera software, with a variety of popular industry-standard EDA simulators and timing analyzers, or with the timing model shown in Figure 13. MAX 7000B devices have predictable internal delays that enable the designer to determine the worst-case timing of any design. The Altera software provides timing simulation, point-to-point delay prediction, and detailed timing analysis for device-wide performance evaluation.

Figure 13. MAX 7000B Timing Model



The timing characteristics of any signal path can be derived from the timing model and parameters of a particular device. External timing parameters, which represent pin-to-pin timing delays, can be calculated as the sum of internal parameters. Figure 14 shows the timing relationship between internal and external delay parameters.



See [Application Note 94 \(Understanding MAX 7000 Timing\)](#) for more information.

Table 19. EPM7032B Internal Timing Parameters *Notes (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-3.5		-5.0		-7.5		
			Min	Max	Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.3		0.5		0.7	ns
t_{IO}	I/O input pad and buffer delay			0.3		0.5		0.7	ns
t_{FIN}	Fast input delay			0.9		1.3		2.0	ns
t_{FIND}	Programmable delay adder for fast input			1.0		1.5		1.5	ns
t_{SEXP}	Shared expander delay			1.5		2.1		3.2	ns
t_{PEXP}	Parallel expander delay			0.4		0.6		0.9	ns
t_{LAD}	Logic array delay			1.4		2.0		3.1	ns
t_{LAC}	Logic control array delay			1.2		1.7		2.6	ns
t_{IOE}	Internal output enable delay			0.1		0.2		0.3	ns
t_{OD1}	Output buffer and pad delay slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		0.9		1.2		1.8	ns
t_{OD3}	Output buffer and pad delay slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		5.9		6.2		6.8	ns
t_{ZX1}	Output buffer enable delay slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		1.6		2.2		3.4	ns
t_{ZX3}	Output buffer enable delay slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		6.6		7.2		8.4	ns
t_{XZ}	Output buffer disable delay	$C1 = 5\text{ pF}$		1.6		2.2		3.4	ns
t_{SU}	Register setup time		0.7		1.1		1.6		ns
t_H	Register hold time		0.4		0.5		0.9		ns
t_{FSU}	Register setup time of fast input		0.8		0.8		1.1		ns
t_{FH}	Register hold time of fast input		1.2		1.2		1.4		ns
t_{RD}	Register delay			0.5		0.6		0.9	ns
t_{COMB}	Combinatorial delay			0.2		0.3		0.5	ns
t_{IC}	Array clock delay			1.2		1.8		2.8	ns
t_{EN}	Register enable time			1.2		1.7		2.6	ns
t_{GLOB}	Global control delay			0.7		1.1		1.6	ns
t_{PRE}	Register preset time			1.0		1.3		1.9	ns
t_{CLR}	Register clear time			1.0		1.3		1.9	ns
t_{PIA}	PIA delay	(2)		0.7		1.0		1.4	ns
t_{LPA}	Low-power adder	(4)		1.5		2.1		3.2	ns

Table 20. EPM7032B Selectable I/O Standard Timing Adder Delays *Notes (1)*

I/O Standard	Parameter	Speed Grade						Unit
		-3.5		-5.0		-7.5		
		Min	Max	Min	Max	Min	Max	
PCI	Input to PIA		0.0		0.0		0.0	ns
	Input to global clock and clear		0.0		0.0		0.0	ns
	Input to fast input register		0.0		0.0		0.0	ns
	All outputs		0.0		0.0		0.0	ns

Notes to tables:

- (1) These values are specified under the Recommended Operating Conditions in [Table 15 on page 29](#). See [Figure 14](#) for more information on switching waveforms.
- (2) These values are specified for a PIA fan-out of all LABs.
- (3) Measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (4) The t_{LPA} parameter must be added to the t_{LAD} , t_{LAC} , t_{IC} , t_{ACL} , t_{CPW} , t_{EN} , and t_{SEXP} parameters for macrocells running in low-power mode.

Table 23. EPM7064B Selectable I/O Standard Timing Adder Delays (Part 2 of 2) *Note (1)*

I/O Standard	Parameter	Speed Grade						Unit
		-3		-5		-7		
		Min	Max	Min	Max	Min	Max	
PCI	Input to PIA		0.0		0.0		0.0	ns
	Input to global clock and clear		0.0		0.0		0.0	ns
	Input to fast input register		0.0		0.0		0.0	ns
	All outputs		0.0		0.0		0.0	ns

Notes to tables:

- (1) These values are specified under the Recommended Operating Conditions in [Table 15 on page 29](#). See [Figure 14](#) for more information on switching waveforms.
- (2) These values are specified for a PIA fan-out of all LABs.
- (3) Measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (4) The t_{LPA} parameter must be added to the t_{LAD} , t_{LAC} , t_{IC} , t_{ACL} , t_{CPPW} , t_{EN} , and t_{SEXP} parameters for macrocells running in low-power mode.

Table 24. EPM7128B External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-4		-7		-10		
			Min	Max	Min	Max	Min	Max	
t _{PD1}	Input to non-registered output	C1 = 35 pF (2)		4.0		7.5		10.0	ns
t _{PD2}	I/O input to non-registered output	C1 = 35 pF (2)		4.0		7.5		10.0	ns
t _{SU}	Global clock setup time	(2)	2.5		4.5		6.1		ns
t _H	Global clock hold time	(2)	0.0		0.0		0.0		ns
t _{FSU}	Global clock setup time of fast input		1.0		1.5		1.5		ns
t _{FH}	Global clock hold time of fast input		1.0		1.0		1.0		ns
t _{FZHSU}	Global clock setup time of fast input with zero hold time		2.0		3.0		3.0		ns
t _{FZHH}	Global clock hold time of fast input with zero hold time		0.0		0.0		0.0		ns
t _{CO1}	Global clock to output delay	C1 = 35 pF	1.0	2.8	1.0	5.7	1.0	7.5	ns
t _{CH}	Global clock high time		1.5		3.0		4.0		ns
t _{CL}	Global clock low time		1.5		3.0		4.0		ns
t _{ASU}	Array clock setup time	(2)	1.2		2.0		2.8		ns
t _{AH}	Array clock hold time	(2)	0.2		0.7		0.9		ns
t _{ACO1}	Array clock to output delay	C1 = 35 pF (2)	1.0	4.1	1.0	8.2	1.0	10.8	ns
t _{ACH}	Array clock high time		1.5		3.0		4.0		ns
t _{ACL}	Array clock low time		1.5		3.0		4.0		ns
t _{CPPW}	Minimum pulse width for clear and preset		1.5		3.0		4.0		ns
t _{CNT}	Minimum global clock period	(2)		4.1		7.9		10.6	ns
f _{CNT}	Maximum internal global clock frequency	(2), (3)	243.9		126.6		94.3		MHz
t _{ACNT}	Minimum array clock period	(2)		4.1		7.9		10.6	ns
f _{ACNT}	Maximum internal array clock frequency	(2), (3)	243.9		126.6		94.3		MHz

Table 25. EPM7128B Internal Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-4		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.3		0.6		0.8	ns
t_{IO}	I/O input pad and buffer delay			0.3		0.6		0.8	ns
t_{FIN}	Fast input delay			1.3		2.9		3.7	ns
t_{FIND}	Programmable delay adder for fast input			1.0		1.5		1.5	ns
t_{SEXP}	Shared expander delay			1.5		2.8		3.8	ns
t_{PEXP}	Parallel expander delay			0.4		0.8		1.0	ns
t_{LAD}	Logic array delay			1.6		2.9		3.8	ns
t_{LAC}	Logic control array delay			1.4		2.6		3.4	ns
t_{IOE}	Internal output enable delay			0.1		0.3		0.4	ns
t_{OD1}	Output buffer and pad delay slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		0.9		1.7		2.2	ns
t_{OD3}	Output buffer and pad delay slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		5.9		6.7		7.2	ns
t_{ZX1}	Output buffer enable delay slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		1.8		3.3		4.4	ns
t_{ZX3}	Output buffer enable delay slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		6.8		8.3		9.4	ns
t_{XZ}	Output buffer disable delay	$C1 = 5\text{ pF}$		1.8		3.3		4.4	ns
t_{SU}	Register setup time		1.0		1.9		2.6		ns
t_H	Register hold time		0.4		0.8		1.1		ns
t_{FSU}	Register setup time of fast input		0.8		0.9		0.9		ns
t_{FH}	Register hold time of fast input		1.2		1.6		1.6		ns
t_{RD}	Register delay			0.5		1.1		1.4	ns
t_{COMB}	Combinatorial delay			0.2		0.3		0.4	ns
t_{IC}	Array clock delay			1.4		2.8		3.6	ns
t_{EN}	Register enable time			1.4		2.6		3.4	ns
t_{GLOB}	Global control delay			1.1		2.3		3.1	ns
t_{PRE}	Register preset time			1.0		1.9		2.6	ns
t_{CLR}	Register clear time			1.0		1.9		2.6	ns
t_{PIA}	PIA delay	(2)		1.0		2.0		2.8	ns
t_{LPA}	Low-power adder	(4)		1.5		2.8		3.8	ns

Table 26. EPM7128B Selectable I/O Standard Timing Adder Delays (Part 2 of 2) *Note (1)*

I/O Standard	Parameter	Speed Grade						Unit
		-4		-7		-10		
		Min	Max	Min	Max	Min	Max	
PCI	Input to PIA		0.0		0.0		0.0	ns
	Input to global clock and clear		0.0		0.0		0.0	ns
	Input to fast input register		0.0		0.0		0.0	ns
	All outputs		0.0		0.0		0.0	ns

Notes to tables:

- (1) These values are specified under the Recommended Operating Conditions in Table 15 on page 29. See Figure 14 for more information on switching waveforms.
- (2) These values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (3) Measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (4) The t_{LPA} parameter must be added to the t_{LAD} , t_{LAC} , t_{IC} , t_{ACL} , t_{CPW} , t_{EN} , and t_{SEXP} parameters for macrocells running in low-power mode.

Table 30. EPM7512B External Timing Parameters *Note (1)*

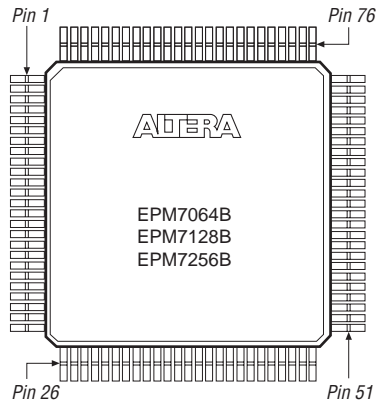
Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t _{PD1}	Input to non-registered output	C1 = 35 pF (2)		5.5		7.5		10.0	ns
t _{PD2}	I/O input to non-registered output	C1 = 35 pF (2)		5.5		7.5		10.0	ns
t _{SU}	Global clock setup time	(2)	3.6		4.9		6.5		ns
t _H	Global clock hold time	(2)	0.0		0.0		0.0		ns
t _{FSU}	Global clock setup time of fast input		1.0		1.5		1.5		ns
t _{FH}	Global clock hold time of fast input		1.0		1.0		1.0		ns
t _{FZHSU}	Global clock setup time of fast input with zero hold time		2.5		3.0		3.0		ns
t _{FZHH}	Global clock hold time of fast input with zero hold time		0.0		0.0		0.0		ns
t _{CO1}	Global clock to output delay	C1 = 35 pF	1.0	3.7	1.0	5.0	1.0	6.7	ns
t _{CH}	Global clock high time		3.0		3.0		4.0		ns
t _{CL}	Global clock low time		3.0		3.0		4.0		ns
t _{ASU}	Array clock setup time	(2)	1.4		1.9		2.5		ns
t _{AH}	Array clock hold time	(2)	0.5		0.6		0.8		ns
t _{ACO1}	Array clock to output delay	C1 = 35 pF (2)	1.0	5.9	1.0	8.0	1.0	10.7	ns
t _{ACH}	Array clock high time		3.0		3.0		4.0		ns
t _{ACL}	Array clock low time		3.0		3.0		4.0		ns
t _{CPPW}	Minimum pulse width for clear and preset		3.0		3.0		4.0		ns
t _{CNT}	Minimum global clock period	(2)		6.1		8.4		11.1	ns
f _{CNT}	Maximum internal global clock frequency	(2), (3)	163.9		119.0		90.1		MHz
t _{ACNT}	Minimum array clock period	(2)		6.1		8.4		11.1	ns
f _{ACNT}	Maximum internal array clock frequency	(2), (3)	163.9		119.0		90.1		MHz

Table 31. EPM7512B Internal Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.3		0.3		0.5	ns
t_{IO}	I/O input pad and buffer delay			0.3		0.3		0.5	ns
t_{FIN}	Fast input delay			2.2		3.2		4.0	ns
t_{FIND}	Programmable delay adder for fast input			1.5		1.5		1.5	ns
t_{SEXP}	Shared expander delay			1.5		2.1		2.7	ns
t_{PEXP}	Parallel expander delay			0.4		0.5		0.7	ns
t_{LAD}	Logic array delay			1.7		2.3		3.0	ns
t_{LAC}	Logic control array delay			1.5		2.0		2.6	ns
t_{IOE}	Internal output enable delay			0.1		0.2		0.2	ns
t_{OD1}	Output buffer and pad delay slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		0.9		1.2		1.6	ns
t_{OD3}	Output buffer and pad delay slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		5.9		6.2		6.6	ns
t_{ZX1}	Output buffer enable delay slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		2.8		3.8		5.0	ns
t_{ZX3}	Output buffer enable delay slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		7.8		8.8		10.0	ns
t_{XZ}	Output buffer disable delay	$C1 = 5\text{ pF}$		2.8		3.8		5.0	ns
t_{SU}	Register setup time		1.5		2.0		2.6		ns
t_H	Register hold time		0.4		0.5		0.7		ns
t_{FSU}	Register setup time of fast input		0.8		1.1		1.1		ns
t_{FH}	Register hold time of fast input		1.2		1.4		1.4		ns
t_{RD}	Register delay			0.5		0.7		1.0	ns
t_{COMB}	Combinatorial delay			0.2		0.3		0.4	ns
t_{IC}	Array clock delay			1.8		2.4		3.1	ns
t_{EN}	Register enable time			1.5		2.0		2.6	ns
t_{GLOB}	Global control delay			2.0		2.8		3.6	ns
t_{PRE}	Register preset time			1.0		1.4		1.9	ns
t_{CLR}	Register clear time			1.0		1.4		1.9	ns
t_{PIA}	PIA delay	(2)		2.4		3.4		4.5	ns
t_{LPA}	Low-power adder	(4)		2.0		2.7		3.6	ns

Figure 23. 100-Pin TQFP Package Pin-Out Diagram

Package outline not drawn to scale.

**Figure 24. 100-Pin FineLine BGA Package Pin-Out Diagram**

Package outline not drawn to scale.

